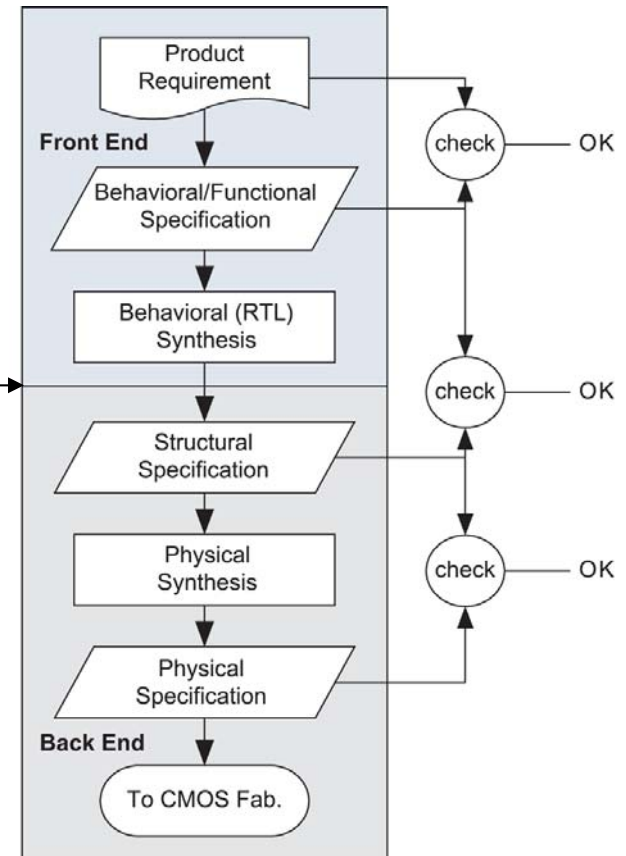
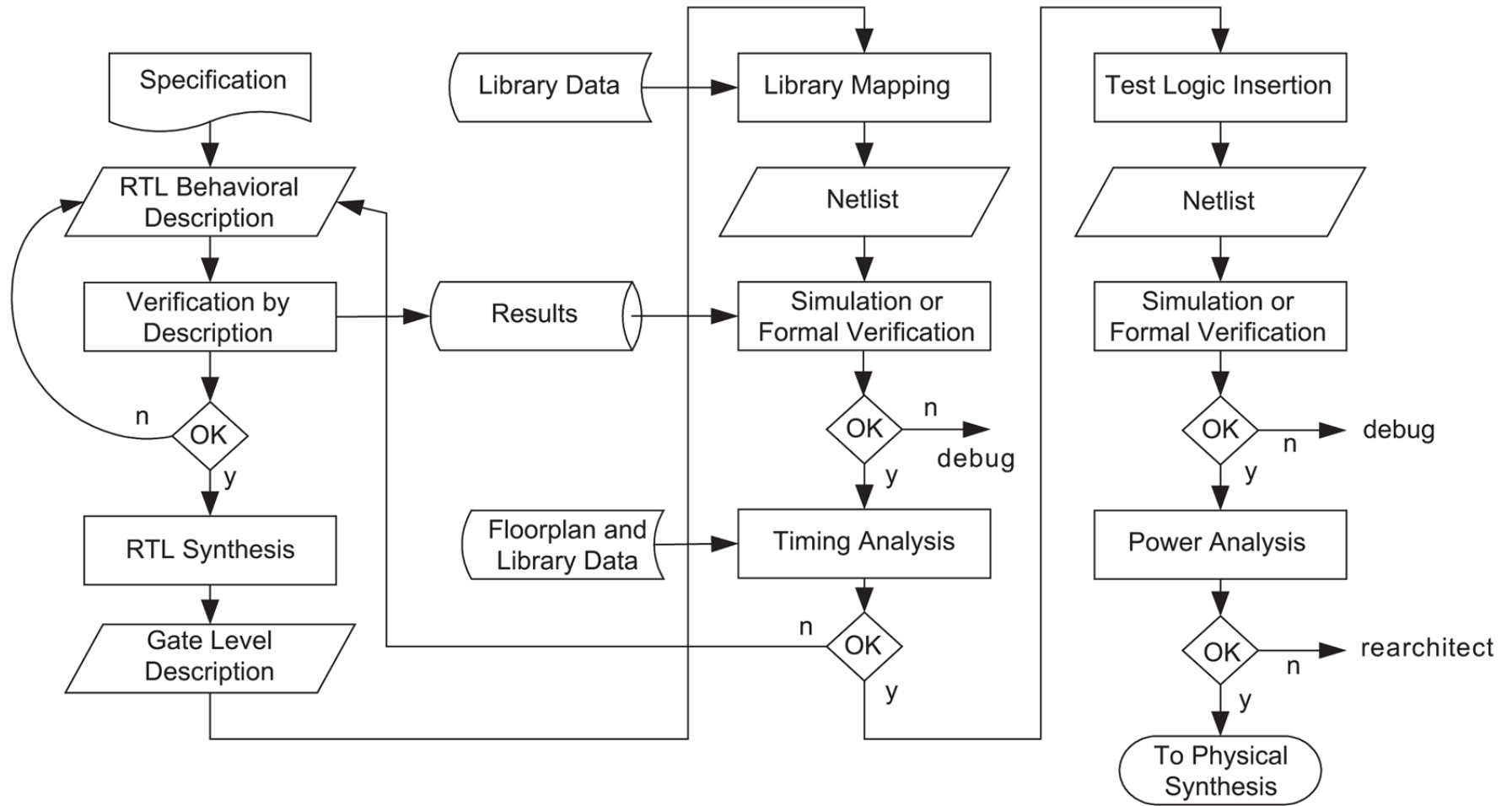


Generalized ASIC Design Flow

- High Level Design
 - ❑ Specification Capture
 - ❑ Design Capture in C, C++, SystemC or SystemVerilog
 - ❑ HW/SW partitioning and IP selection
 - RTL Design
 - ❑ Verilog/VHDL
 - System, Timing and Logic Verification
 - ❑ Is the logic working correctly?
-
- Physical Design
 - ❑ Floorplanning, Place and Route, Clock insertion
 - Performance and Manufacturability Verification
 - ❑ Extraction of Physical View
 - ❑ Verification of timing and signal integrity
 - ❑ Design Rule Checking/ LVS



RTL Synthesis Flow



Logic Design and Verification

- **Design starts with a specification**
 - Text description or system specification language
 - Example: C, SystemC, SystemVerilog

- **RTL Description**
 - Automated conversion from system specification to RTL possible
 - Example: Cadence C-to-Silicon Compiler
 - Most often designer manually converts to Verilog or VHDL

- **Verification**
 - Generate test-benches and run simulations to verify functionality
 - Assertion based verification
 - Automated test-bench generation

RTL Synthesis and Verification

○ RTL Synthesis

- ❑ Automated generation of generic gate description from RTL description
- ❑ Logic optimization for speed and area
- ❑ State machine decomposition, datapath optimization, power optimization
- ❑ Modern tools integrate global place-and-route capabilities

○ Library Mapping

- ❑ Translates a generic gate level description to a netlist using a target library

○ Functional or Formal Verification

- ❑ HDL ambiguities can cause the synthesis tool to produce incorrect netlist
- ❑ Rerun functional verification on the gate level netlist
- ❑ Formal verification
 - Model checking: prove that certain assertions are true
 - Equivalence checking: compare two design descriptions

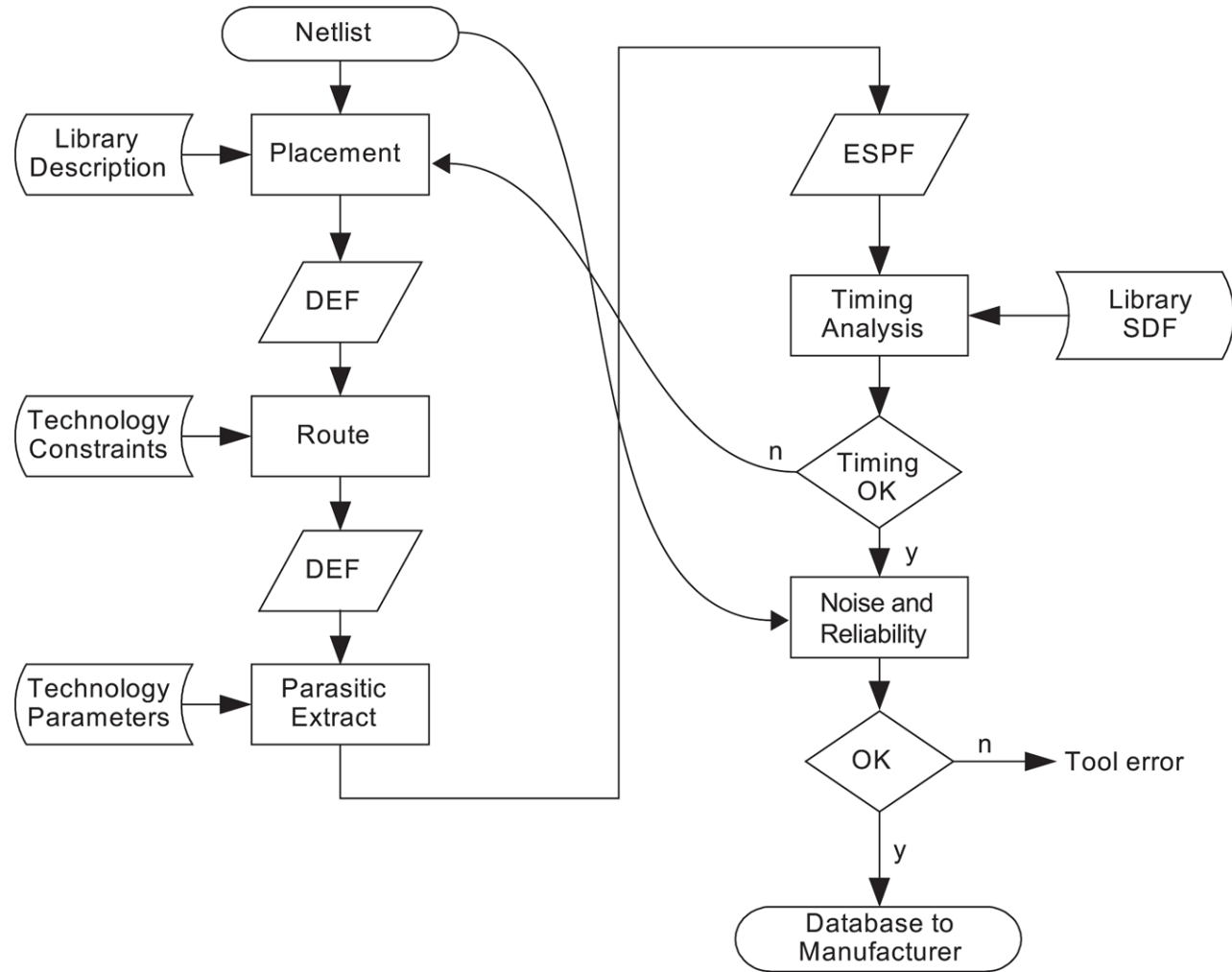
Static Timing Analysis

- Checks temporal requirements of the design
- Uses intrinsic gate delay information and estimated routing loads to exhaustively evaluate all timing paths
- Requires timing information for any macro-blocks e.g. memories
- Will evaluate set-up and hold-time violations
- Special cases need to be flagged using timing constraints (more later)
- Reports “slack time”
- Re-synthesize the circuit or re-design to improve delay

Test Insertion and Power Analysis

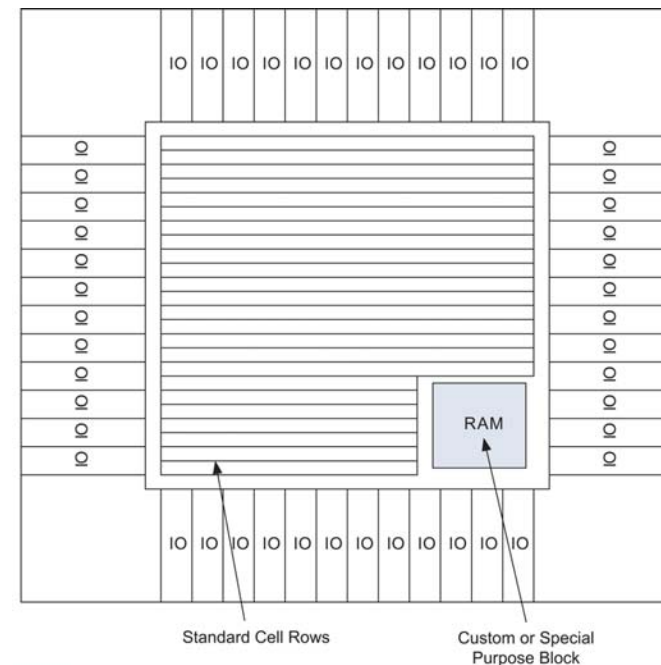
- Insert various DFT features to perform device testing using Automated Test Equipment (ATE) and system level tests
 - Scan enabled flip-flops and scan chains
 - Automatic Test Pattern Generation (ATPG) tools generate test vectors to perform logic and parametric testing
 - Built-in Self Test
 - Logic: Based on LFSR (random-patterns) and MISR (signature) (LBIST)
 - Memory: Implements various memory testing algorithms (MBIST)
 - Boundary-Scan/JTAG
 - Enables board/system level testing
 - More on DFT and test insertion later
- **Power Analysis**
 - Power analysis tools predict power consumption of the circuit
 - Either test vectors or probabilistic activity factors used for estimation

Standard Cell Place and Route Flow



Floorplanning /Placement/Routing

- Manually place major modules in the chip depending on connections with other modules
- Standard cell rows are defined next and the gates are placed
 - No routing channels between rows in newer technologies
- Timing driven placement tries to minimize delay on critical paths
- Routing
 - Route special nets
 - Power, Ground
 - Clock tree synthesis/ routing
 - Minimize skew
 - Insert buffers
 - Global and detailed routing of signal nets



Verification Steps

○ Parasitic Extraction

- ❑ Detailed parasitic extraction after routing
- ❑ 2D, 2.5D and 3D extraction possible, output is SPEF, RSPF, ESPF etc.

○ Timing Analysis

- ❑ Static timing analysis, iterate if there are problems
- ❑ If possible, full chip simulation at transistor-level using “fast spice simulators”
 - E.g. Nanosim, Ultrasim

○ Crosstalk, V_{DD} Drop, Electromigration Analysis

○ Power Analysis

- ❑ More detailed wire capacitance available for power analysis, iterate if there are problems

Timing Driven Placement

